

SID4-SWIR

WAVE FRONT SENSOR



↓ SPECIFICATIONS

Wavelength range	0.9 – 1.7 μm
Aperture dimensions	9.60 x 7.68 mm ²
Spatial resolution	120 μm
Phase and intensity Sampling	80 X 64
Accuracy	15 nm RMS
Resolution (Phase)	<2nm RMS
Acquisition rate	120 fps
Real-time processing frequency	> 7 fps (full resolution)
Interface	Giga Ethernet
Dimensions	100 x 55 x 63 mm
Weight	455 g

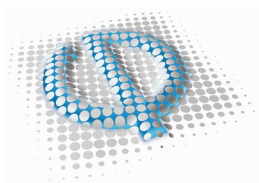
→ The SID4-SWIR wavefront sensor integrates Phasics patented technology with an In-GaAs detector. Thanks to its high spatial resolution and great sensitivity, it offers accurate wavefront measurement over its whole spectral range **from 900 nm to 1.7 μm** .

The SID4-SWIR is an innovative solution for **testing SWIR lens** used in optical communications, inspection instruments or night vision in military and surveillance devices. It provides both MTF and aberrations at once.

The SID4-SWIR also enables characterizing SWIR sources like 1.55 μm lasers or LEDs for laser guiding systems.

↘ KEY FEATURES

- Extended spectral range from 0.9 to 1.7 μm
- High resolution – 80 X 64
- High sensitivity - <2nm phase noise through the whole spectral range (compatible with low energy IR source)
- High stability
- Cooled detector
- Compact & Cost effective

**PHASICS S.A.**

Bâtiment Explorer
Espace Technologique
Route de l'Orme des Merisiers
91190 Saint-Aubin
FRANCE
Tel : +33(0)1 80 75 06 33

contact@phasics.fr

www.phasics.com

PHASICS CORP.

600 California Street
11th Floor
San Francisco CA 94108
USA
Tel : +1 415 610 9741